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#### Abstract of JP9322896

**PROBLEM TO BE SOLVED:** To reduce the physical quantity of circuits without degrading the directivity of beams by performing an electron sector scanning by using a first group of beam formers which add input signals obtained from multiple groups of vibrators after they are delayed and a second group of beam formers which have the output thereof as common input. **SOLUTION:** Signals inputted into vibrators 1-16 of a probe 100 are inputted into four beam formers 101-104 and then, into the second stage of beam formers 111 and 112, which 111 and 112 are provided with two types of delay wire, the one of which is delay wires 50-52 and 53-55 to control the angle of beam deflection and the other of which is delay wires 60-61 and 62-63 to control focusing. In the beam former 111, the angle of beam deflection is turned to the direction of 200A by the delay wires 50-53 and moreover, the focusing position of beams is set to 201A by the delay wires 60 and 61. In the beam former 112, the angle of deflection angle is turned to the direction of 200B by the delay wires 53-55 and moreover, the focusing position of the beams is set to 201B by the delay wires 62 and 63.

